



F40N25-HC

POWER MOSFET

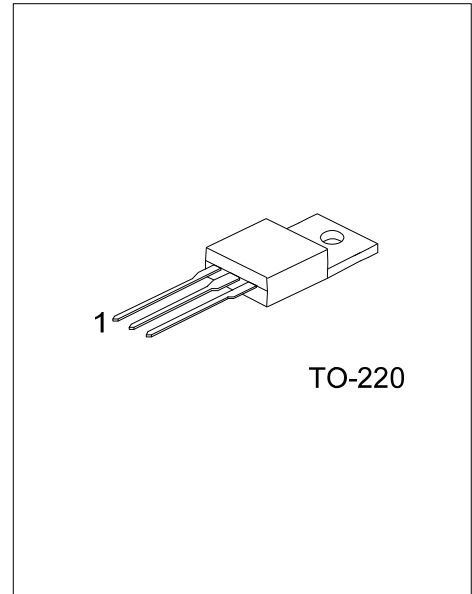
40A, 250V N-CHANNEL POWER MOSFET

DESCRIPTION

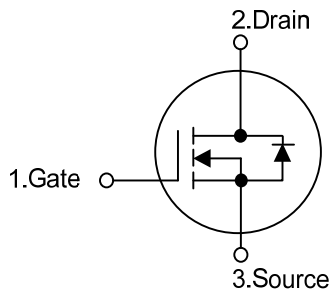
The UTC **F40N25-HC** N-Channel enhancement mode silicon gate power MOSFET with Fast Body Diode. is designed high voltage, high speed power switching applications such. such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics.

FEATURES

- * $R_{DS(ON)} \leq 68 \text{ m}\Omega$ @ $V_{GS}=10\text{V}$, $I_D=20\text{A}$
- * Fast body diode MOSFET technology
- * Low switching losses due to reduced Q_{rr}
- * Fast Switching Speeds
- * 100% avalanche tested
- * Linear Transfer Characteristics
- * High Input Impedance
- * Avalanche energy tested



SYMBOL



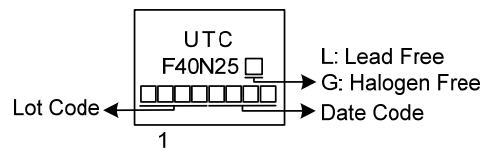
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
F40N25L-TA3-T	F40N25G-TA3-T	TO-220	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

F40N25G-TA3-T		(1)Packing Type	(1) T: Tube
		(2)Package Type	(2) TA3: TO-220
		(3)Green Package	(3) G: Halogen Free and Lead Free L: Lead Free

■ MARKING



■ **ABSOLUTE MAXIMUM RATING** ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	V_{DS}	250	V
Gate-Source Voltage	V_{GS}	± 30	V
Drain Current	DC	I_D	40
	Pulsed (Note 2)	I_{DM}	80
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	760
Peak Diode Recovery dv/dt (Note 4)	dv/dt	5.3	V/ns
Power Dissipation	P_D	135	W
Junction Temperature	T_J	+150	$^{\circ}\text{C}$
Storage Temperature Range	T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L=1\text{mH}$, $I_{AS} = 39\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\Omega$, Starting $T_J=25^{\circ}\text{C}$.

4. $I_{SD} \leq 30\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DS}$, Starting $T_J=25^{\circ}\text{C}$.

■ **THERMAL DATA**

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	62.5	$^{\circ}\text{C}/\text{W}$
Junction to Case	θ_{JC}	0.92	$^{\circ}\text{C}/\text{W}$

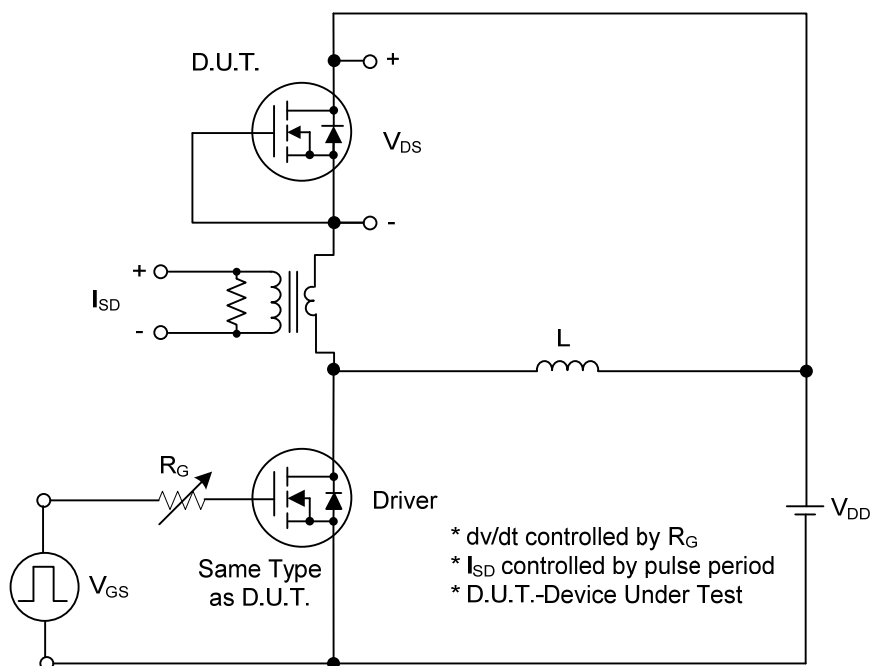
■ ELECTRICAL CHARACTERISTICS (T_J=25°C unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	V _{GS} =0V, I _D =250μA	250			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} =250V, V _{GS} =0V			10	μA
Gate-Source Leakage Current	Forward	I _{GSS}	V _{GS} =+30V, V _{DS} =0V			+100	nA
	Reverse		V _{GS} =-30V, V _{DS} =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	2.0		4.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =20A			68	mΩ
DYNAMIC PARAMETERS							
Input Capacitance		C _{ISS}	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		3100		pF
Output Capacitance		C _{OSS}			940		pF
Reverse Transfer Capacitance		C _{RSS}			235		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q _G	V _{DS} =200V, V _{GS} =10V, I _D =40A (Note 1, 2)		108		nC
Gate to Source Charge		Q _{GS}			31		nC
Gate to Drain Charge		Q _{GD}			34		nC
Turn-ON Delay Time		t _{D(ON)}	V _{DD} =100V, V _{GS} =10V, I _D =40A, R _G =3Ω (Note 1, 2)		14		ns
Rise Time		t _R			21		ns
Turn-OFF Delay Time		t _{D(OFF)}			52		ns
Fall-Time		t _F			19		ns
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Continuous Drain-Source Diode Forward Current		I _S				40	A
Maximum Pulsed Drain-Source Diode Forward Current		I _{SM}				80	A
Diode Forward Voltage		V _{SD}	I _F =40A, V _{GS} =0V			1.4	V
Reverse Recovery Time		t _{rr}	I _S =30A, V _{GS} =0V,		118		ns
Reverse Recovery Charge (Note 1)		Q _{rr}	dI _F /dt = 100 A/μs		415		nC

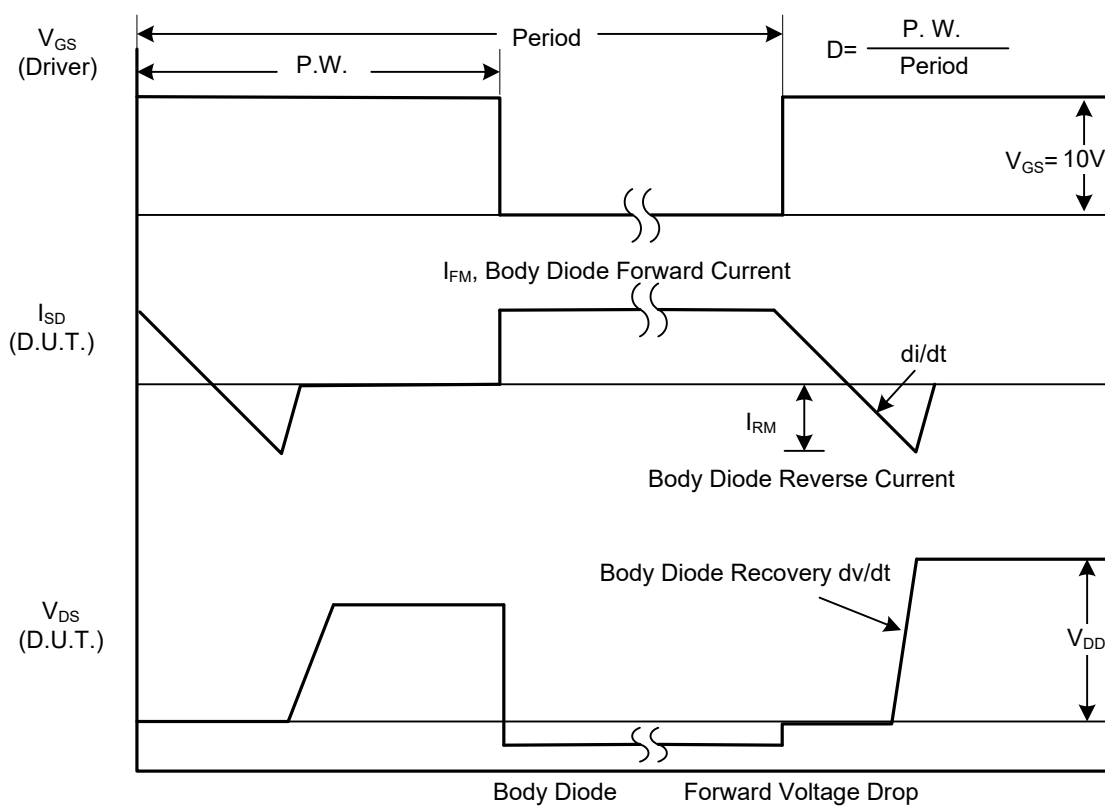
Notes: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

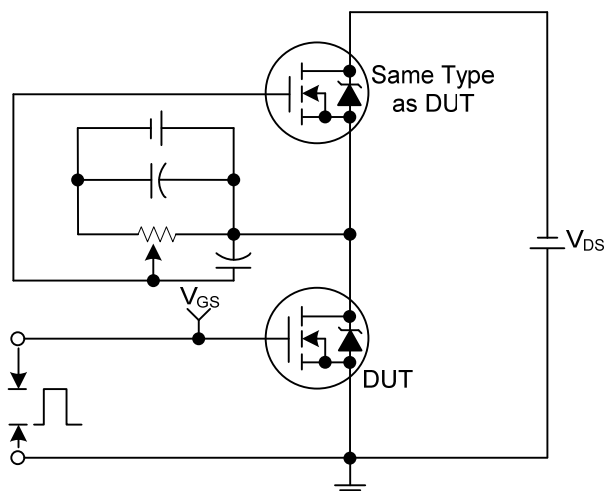


Peak Diode Recovery dv/dt Test Circuit

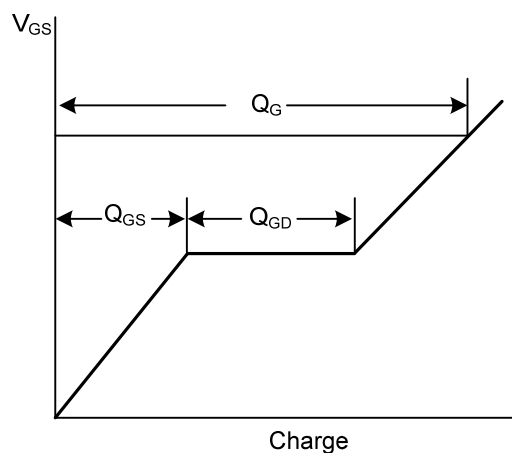


Peak Diode Recovery dv/dt Waveforms

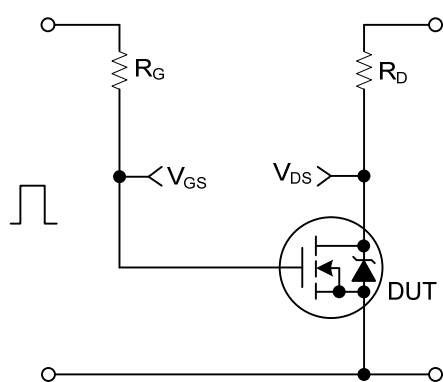
■ TEST CIRCUITS AND WAVEFORMS



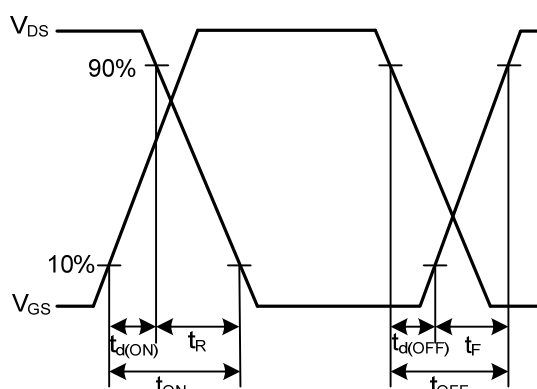
Gate Charge Test Circuit



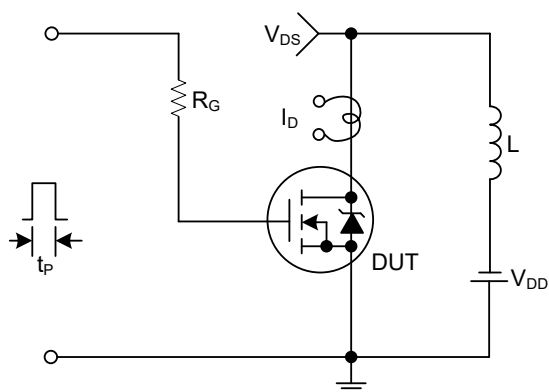
Gate Charge Waveforms



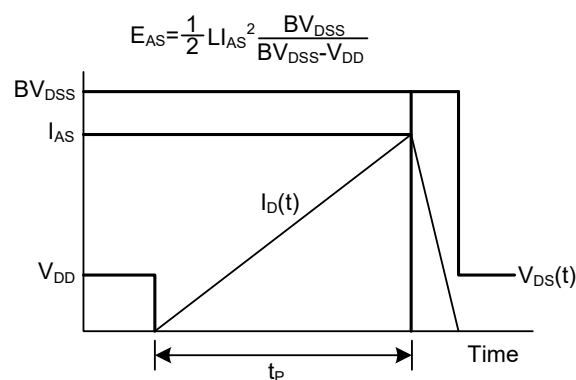
Resistive Switching Test Circuit



Resistive Switching Waveforms

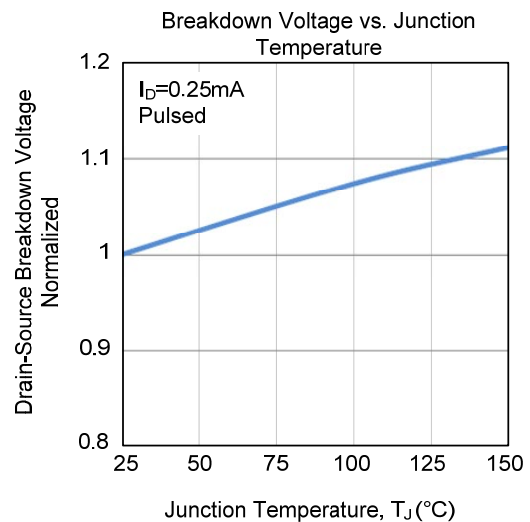
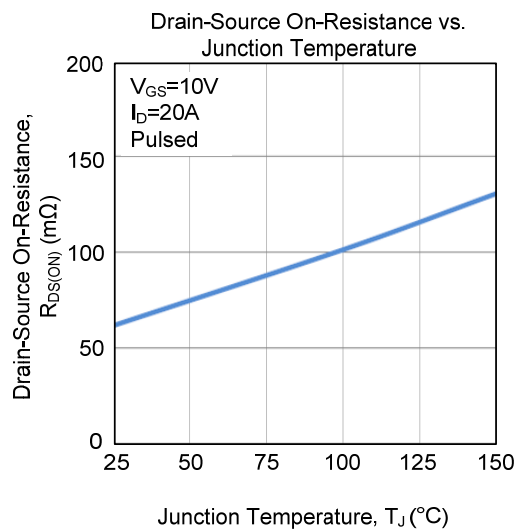
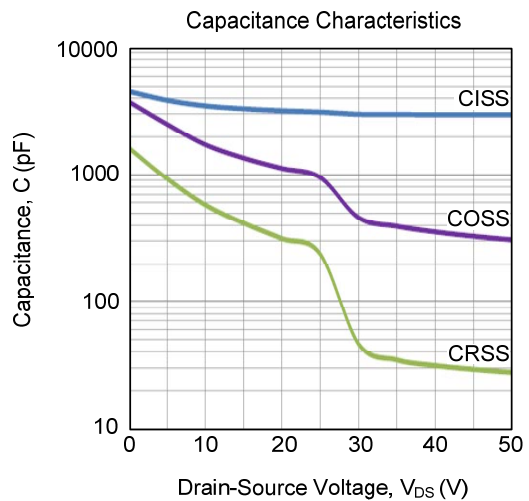
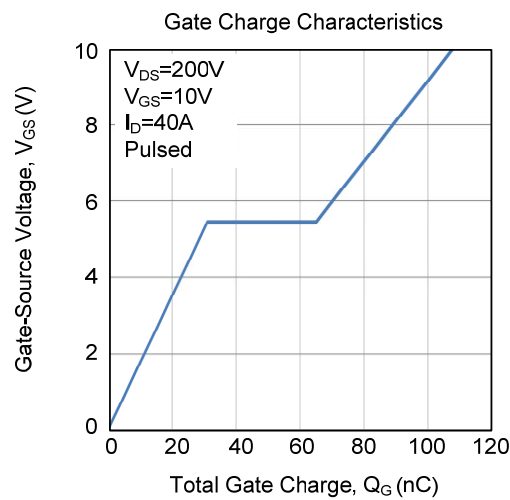
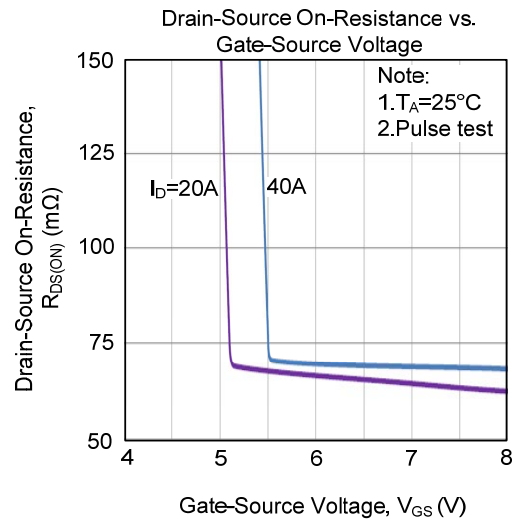
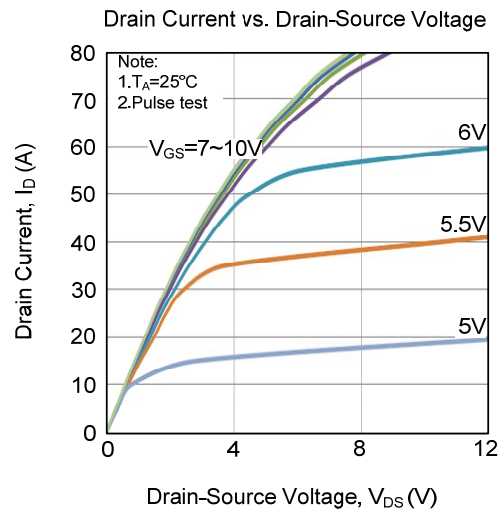


Unclamped Inductive Switching Test Circuit

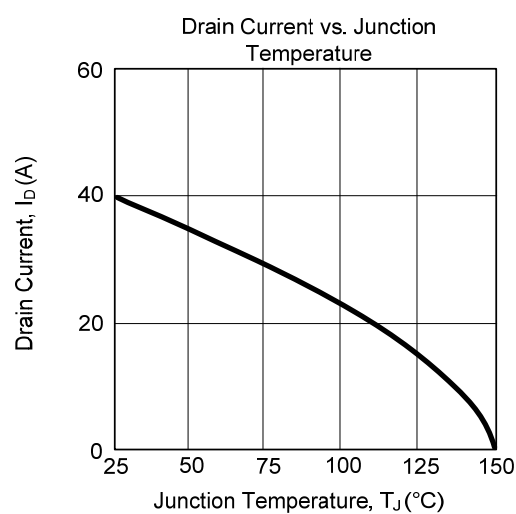
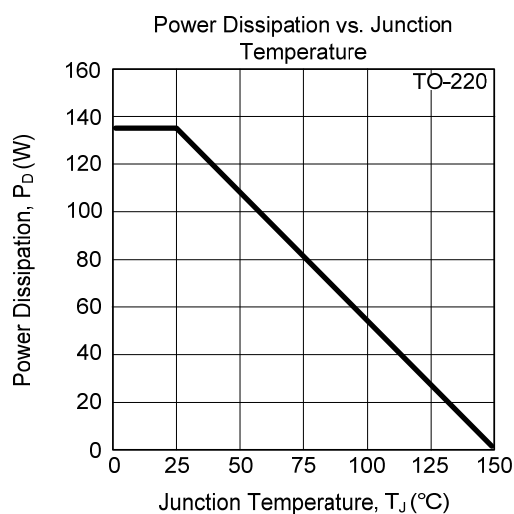
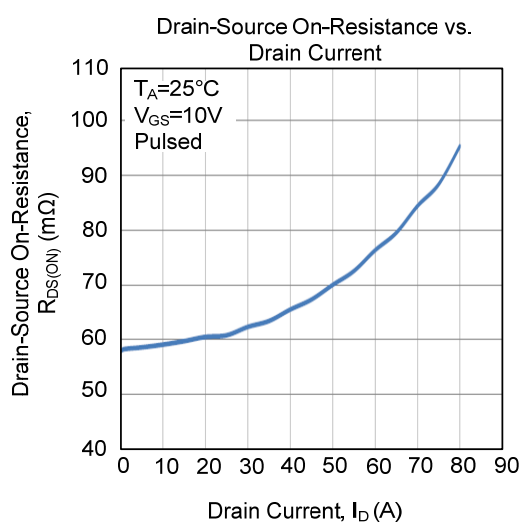
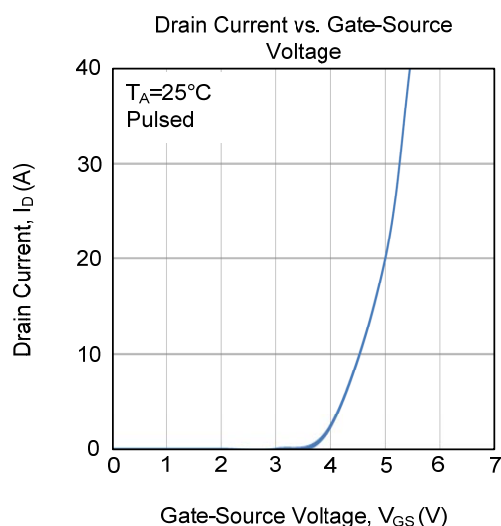
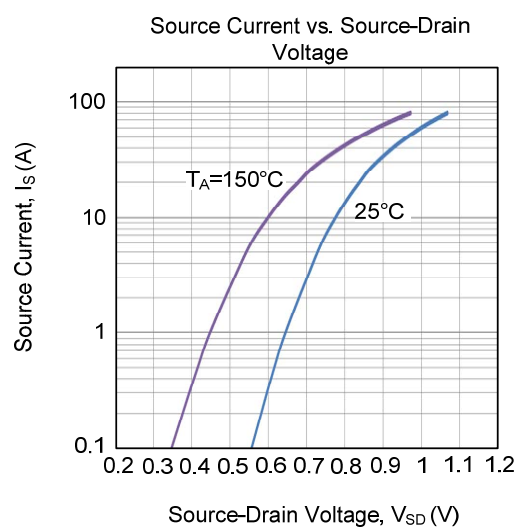
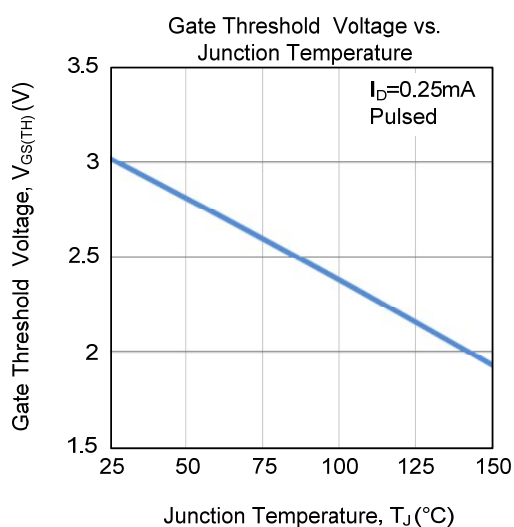


Unclamped Inductive Switching Waveforms

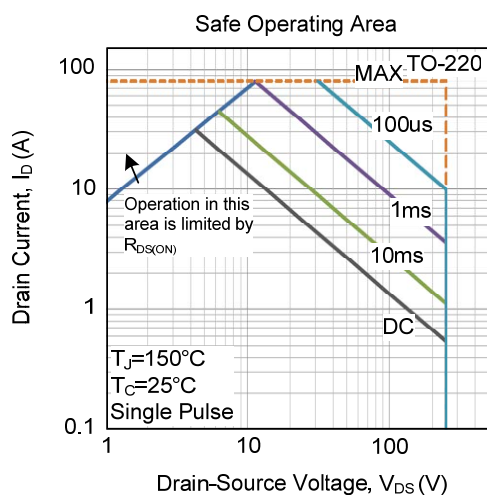
TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



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